

Notice of References Cited	Application/Control No. 10/628,500		Applicant(s)/Patent Under Reexamination MIYAZAWA ET AL.	
	Examiner Khiem D. Nguyen		Art Unit 2823	Page 1 of 1

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NON-PATENT DOCUMENTS

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	U	Patent Abstracts Of Japan (Publication number 2000-208707) "Semiconductor Device and Control Method for Terminal Capacitance of the Device", Kurihara Yusho (28.07.2000).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.